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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	6000
Total RAM Bits	184320
Number of I/O	100
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	196-TFBGA, CSBGA
Supplier Device Package	196-CSPBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7s6-2cpga196i

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
FPGA Logic					
$V_{CCINT}^{(3)}$	For -2 and -1 (1.0V) devices: internal supply voltage.	0.95	1.00	1.05	V
	For -1L (0.95V) devices: internal supply voltage.	0.92	0.95	0.98	V
V_{CCAUX}	Auxiliary supply voltage.	1.71	1.80	1.89	V
$V_{CCBRAM}^{(3)}$	For -2 and -1 (1.0V) devices: block RAM supply voltage.	0.95	1.00	1.05	V
	For -1L (0.95V) devices: block RAM supply voltage.	0.92	0.95	0.98	V
$V_{CCO}^{(4)(5)}$	Supply voltage for HR I/O banks.	1.14	–	3.465	V
$V_{IN}^{(6)}$	I/O input voltage.	–0.20	–	$V_{CCO} + 0.20$	V
	I/O input voltage (when $V_{CCO} = 3.3V$) for V_{REF} and differential I/O standards except TMDS_33. ⁽⁷⁾	–0.20	–	2.625	V
$I_{IN}^{(8)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	–	10	mA
$V_{CCBATT}^{(9)}$	Battery voltage.	1.0	–	1.89	V
XADC					
V_{CCADC}	XADC supply relative to GNDADC.	1.71	1.80	1.89	V
V_{REFP}	Externally supplied reference voltage.	1.20	1.25	1.30	V
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices.	0	–	85	°C
	Junction temperature operating range for industrial (I) temperature devices.	–40	–	100	°C
	Junction temperature operating range for expanded (Q) temperature devices.	–40	–	125	°C

Notes:

- All voltages are relative to ground.
- For the design of the power distribution system consult the *7 Series FPGAs PCB Design Guide* (UG483) [Ref 5].
- If V_{CCINT} and V_{CCBRAM} are operating at the same voltage, V_{CCINT} and V_{CCBRAM} should be connected to the same supply.
- Configuration data is retained even if V_{CCO} drops to 0V.
- Includes V_{CCO} of 1.2V, 1.35V, 1.5V, 1.8V, 2.5V, and 3.3V at $\pm 5\%$.
- The lower absolute voltage specification always applies.
- See Table 9 for TMDS_33 specifications.
- A total of 200 mA per bank should not be exceeded.
- V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX} .

Table 4: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for HR I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI at -40°C to 125°C	AC Voltage Undershoot	% of UI at -40°C to 125°C
$V_{CCO} + 0.55$	100	-0.40	100
		-0.45	61.7
		-0.50	25.8
		-0.55	11.0
$V_{CCO} + 0.60$	46.6	-0.60	4.77
$V_{CCO} + 0.65$	21.2	-0.65	2.10
$V_{CCO} + 0.70$	9.75	-0.70	0.94
$V_{CCO} + 0.75$	4.55	-0.75	0.43
$V_{CCO} + 0.80$	2.15	-0.80	0.20
$V_{CCO} + 0.85$	1.02	-0.85	0.09
$V_{CCO} + 0.90$	0.49	-0.90	0.04
$V_{CCO} + 0.95$	0.24	-0.95	0.02

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. The peak voltage of the overshoot or undershoot, and the duration above $V_{CCO} + 0.20\text{V}$ or below $\text{GND} - 0.20\text{V}$, must not exceed the values in this table.

 Table 5: Typical Quiescent Supply Current⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Device	Speed Grade						Units
			1.0V					0.95V	
			-2C	-2I	-1C	-1I	-1Q	-1LI	
I_{CCINTQ}	Quiescent V_{CCINT} supply current.	XC7S6	36	36	36	36	36	32	mA
		XC7S15	36	36	36	36	36	32	mA
		XC7S25	48	48	48	48	48	43	mA
		XC7S50	95	95	95	95	95	59	mA
		XC7S75	148	148	148	148	148	134	mA
		XC7S100	148	148	148	148	148	134	mA
		XA7S6	N/A	36	N/A	36	36	N/A	mA
		XA7S15	N/A	36	N/A	36	36	N/A	mA
		XA7S25	N/A	48	N/A	48	48	N/A	mA
		XA7S50	N/A	95	N/A	95	95	N/A	mA
		XA7S75	N/A	148	N/A	148	148	N/A	mA
		XA7S100	N/A	148	N/A	148	148	N/A	mA

Table 5: Typical Quiescent Supply Current⁽¹⁾⁽²⁾⁽³⁾ (Cont'd)

Symbol	Description	Device	Speed Grade						Units
			1.0V					0.95V	
			-2C	-2I	-1C	-1I	-1Q	-1LI	
I _{CCOQ}	Quiescent V _{CCO} supply current.	XC7S6	1	1	1	1	1	1	mA
		XC7S15	1	1	1	1	1	1	mA
		XC7S25	1	1	1	1	1	1	mA
		XC7S50	1	1	1	1	1	1	mA
		XC7S75	4	4	4	4	4	4	mA
		XC7S100	4	4	4	4	4	4	mA
		XA7S6	N/A	1	N/A	1	1	N/A	mA
		XA7S15	N/A	1	N/A	1	1	N/A	mA
		XA7S25	N/A	1	N/A	1	1	N/A	mA
		XA7S50	N/A	1	N/A	1	1	N/A	mA
		XA7S75	N/A	4	N/A	4	4	N/A	mA
		XA7S100	N/A	4	N/A	4	4	N/A	mA
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current.	XC7S6	10	10	10	10	10	10	mA
		XC7S15	10	10	10	10	10	10	mA
		XC7S25	13	13	13	13	13	13	mA
		XC7S50	22	22	22	22	22	20	mA
		XC7S75	43	43	43	43	43	43	mA
		XC7S100	43	43	43	43	43	43	mA
		XA7S6	N/A	10	N/A	10	10	N/A	mA
		XA7S15	N/A	10	N/A	10	10	N/A	mA
		XA7S25	N/A	13	N/A	13	13	N/A	mA
		XA7S50	N/A	22	N/A	22	22	N/A	mA
		XA7S75	N/A	43	N/A	43	43	N/A	mA
		XA7S100	N/A	43	N/A	43	43	N/A	mA

Table 6 shows the minimum current, in addition to I_{CCQ} maximum, that is required by Spartan-7 devices for proper power-on and configuration. If the current minimums shown in Table 6 are met, the device powers on after all four supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied. Once initialized and configured, use the *Xilinx Power Estimator* spreadsheet tool [Ref 6] to estimate current drain on these supplies.

Table 6: Power-On Current

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	$I_{CCBRAMMIN}$	Units
XC7S6	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7S15	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7S25	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7S50	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7S75	$I_{CCINTQ} + 300$	$I_{CCAUXQ} + 140$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7S100	$I_{CCINTQ} + 300$	$I_{CCAUXQ} + 140$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XA7S6	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XA7S15	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XA7S25	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XA7S50	$I_{CCINTQ} + 120$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XA7S75	$I_{CCINTQ} + 300$	$I_{CCAUXQ} + 140$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XA7S100	$I_{CCINTQ} + 300$	$I_{CCAUXQ} + 140$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA

Table 7: Power Supply Ramp Time

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT} .		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO} .		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX} .		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of V_{CCBRAM} .		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$.	$T_J = 125^\circ C^{(1)}$	–	300	ms
		$T_J = 100^\circ C^{(1)}$	–	500	ms
		$T_J = 85^\circ C^{(1)}$	–	800	ms

Notes:

- Based on 240,000 power cycles with a nominal V_{CCO} of 3.3V or 36,500 power cycles with a worst case V_{CCO} of 3.465V.

Table 9: Differential SelectIO DC Input and Output Levels

I/O Standard	$V_{ICM}^{(1)}$			$V_{ID}^{(2)}$			$V_{OCM}^{(3)}$			$V_{OD}^{(4)}$		
	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max
BLVDS_25	0.300	1.200	1.425	0.100	–	–	–	1.250	–	Note 5		
MINI_LVDS_25	0.300	1.200	V_{CCAUX}	0.200	0.400	0.600	1.000	1.200	1.400	0.300	0.450	0.600
PPDS_25	0.200	0.900	V_{CCAUX}	0.100	0.250	0.400	0.500	0.950	1.400	0.100	0.250	0.400
RSDS_25	0.300	0.900	1.500	0.100	0.350	0.600	1.000	1.200	1.400	0.100	0.350	0.600
TMDS_33	2.700	2.965	3.230	0.150	0.675	1.200	$V_{CCO} - 0.405$	$V_{CCO} - 0.300$	$V_{CCO} - 0.190$	0.400	0.600	0.800

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage ($Q - \bar{Q}$).
3. V_{OCM} is the output common mode voltage.
4. V_{OD} is the output differential voltage ($Q - \bar{Q}$).
5. V_{OD} for BLVDS will vary significantly depending on topology and loading.

Table 10: Complementary Differential SelectIO DC Input and Output Levels

I/O Standard	$V_{ICM}^{(1)}$			$V_{ID}^{(2)}$		$V_{OL}^{(3)}$	$V_{OH}^{(4)}$	I_{OL}	I_{OH}
	V, Min	V, Typ	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min
DIFF_HSTL_I	0.300	0.750	1.125	0.100	–	0.400	$V_{CCO} - 0.400$	8.00	–8.00
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	–	0.400	$V_{CCO} - 0.400$	8.00	–8.00
DIFF_HSTL_II	0.300	0.750	1.125	0.100	–	0.400	$V_{CCO} - 0.400$	16.00	–16.00
DIFF_HSTL_II_18	0.300	0.900	1.425	0.100	–	0.400	$V_{CCO} - 0.400$	16.00	–16.00
DIFF_HSUL_12	0.300	0.600	0.850	0.100	–	20% V_{CCO}	80% V_{CCO}	0.100	–0.100
DIFF_MOBILE_DDR	0.300	0.900	1.425	0.100	–	10% V_{CCO}	90% V_{CCO}	0.100	–0.100
DIFF_SSTL135	0.300	0.675	1.000	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	13.0	–13.0
DIFF_SSTL135_R	0.300	0.675	1.000	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	8.9	–8.9
DIFF_SSTL15	0.300	0.750	1.125	0.100	–	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	13.0	–13.0
DIFF_SSTL15_R	0.300	0.750	1.125	0.100	–	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	8.9	–8.9
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	–	$(V_{CCO}/2) - 0.470$	$(V_{CCO}/2) + 0.470$	8.00	–8.00
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	–	$(V_{CCO}/2) - 0.600$	$(V_{CCO}/2) + 0.600$	13.4	–13.4

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage ($Q - \bar{Q}$).
3. V_{OL} is the single-ended low-output voltage.
4. V_{OH} is the single-ended high-output voltage.

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications from the Vivado® Design Suite as outlined in [Table 12](#).

Table 12: Speed Specification Version By Device

2018.2.1	Device
1.23	XC7S6, XC7S15, XC7S25, XC7S50, XC7S75, XC7S100
1.16	XA7S6, XA7S15, XA7S25, XA7S50, XA7S75, XA7S100

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows.

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Spartan-7 FPGAs.

Table 17: IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T_{IOPI}			T_{IOOP}			T_{IOTP}			Units
	V_{CCINT} Operating Voltage and Speed Grade									
	1.0V		0.95V	1.0V		0.95V	1.0V		0.95V	
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVC MOS15_F8	0.86	0.93	0.93	1.72	1.98	1.98	1.75	1.99	1.99	ns
LVC MOS15_F12	0.86	0.93	0.93	1.47	1.73	1.73	1.50	1.74	1.74	ns
LVC MOS15_F16	0.86	0.93	0.93	1.46	1.71	1.71	1.49	1.73	1.73	ns
LVC MOS12_S4	0.95	1.02	1.02	2.69	2.95	2.95	2.72	2.96	2.96	ns
LVC MOS12_S8	0.95	1.02	1.02	2.21	2.46	2.46	2.24	2.48	2.48	ns
LVC MOS12_S12	0.95	1.02	1.02	1.91	2.17	2.17	1.94	2.18	2.18	ns
LVC MOS12_F4	0.95	1.02	1.02	2.10	2.35	2.35	2.13	2.37	2.37	ns
LVC MOS12_F8	0.95	1.02	1.02	1.66	1.92	1.92	1.69	1.93	1.93	ns
LVC MOS12_F12	0.95	1.02	1.02	1.51	1.76	1.76	1.54	1.77	1.77	ns
SSTL135_S	0.75	0.82	0.82	1.47	1.73	1.73	1.50	1.74	1.74	ns
SSTL15_S	0.68	0.75	0.75	1.43	1.68	1.68	1.46	1.69	1.69	ns
SSTL18_I_S	0.75	0.82	0.82	1.79	2.04	2.04	1.82	2.06	2.06	ns
SSTL18_II_S	0.75	0.82	0.82	1.43	1.68	1.68	1.46	1.70	1.70	ns
DIFF_SSTL135_S	0.76	0.83	0.83	1.47	1.73	1.73	1.50	1.74	1.74	ns
DIFF_SSTL15_S	0.76	0.83	0.83	1.43	1.68	1.68	1.46	1.69	1.69	ns
DIFF_SSTL18_I_S	0.79	0.86	0.86	1.80	2.06	2.06	1.83	2.07	2.07	ns
DIFF_SSTL18_II_S	0.79	0.86	0.86	1.51	1.76	1.76	1.54	1.77	1.77	ns
SSTL135_F	0.75	0.82	0.82	1.24	1.49	1.49	1.27	1.51	1.51	ns
SSTL15_F	0.68	0.75	0.75	1.19	1.45	1.45	1.22	1.46	1.46	ns
SSTL18_I_F	0.75	0.82	0.82	1.24	1.49	1.49	1.27	1.51	1.51	ns
SSTL18_II_F	0.75	0.82	0.82	1.24	1.49	1.49	1.27	1.51	1.51	ns
DIFF_SSTL135_F	0.76	0.83	0.83	1.24	1.49	1.49	1.27	1.51	1.51	ns
DIFF_SSTL15_F	0.76	0.83	0.83	1.19	1.45	1.45	1.22	1.46	1.46	ns
DIFF_SSTL18_I_F	0.79	0.86	0.86	1.35	1.60	1.60	1.38	1.62	1.62	ns
DIFF_SSTL18_II_F	0.79	0.86	0.86	1.33	1.59	1.59	1.36	1.60	1.60	ns

Table 18 specifies the values of T_{IOTPHZ} and $T_{IOIBUFDISABLE}$. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). $T_{IOIBUFDISABLE}$ is described as the IOB delay from IBUFDISABLE to O output. In HR I/O banks, the internal IN_TERM termination turn-off time is always faster than T_{IOTPHZ} when the INTERMDISABLE pin is used.

Table 22: OLOGIC Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Setup/Hold					
T _{ODCK} /T _{OCKD}	D1/D2 pins setup/hold with respect to CLK.	0.71/–0.11	0.84/–0.11	0.84/–0.11	ns
T _{OOCECK} /T _{OCKOCE}	OCE pin setup/hold with respect to CLK.	0.34/0.58	0.51/0.58	0.51/0.58	ns
T _{OSRCK} /T _{OCKSR}	SR pin setup/hold with respect to CLK.	0.44/0.21	0.80/0.21	0.80/0.21	ns
T _{OTCK} /T _{OCKT}	T1/T2 pins setup/hold with respect to CLK.	0.73/–0.14	0.89/–0.14	0.89/–0.14	ns
T _{OTCECK} /T _{OCKTCE}	TCE pin setup/hold with respect to CLK.	0.34/0.01	0.51/0.01	0.51/0.01	ns
Combinatorial					
T _{ODQ}	D1 to OQ out or T1 to TQ out.	0.96	1.16	1.16	ns
Sequential Delays					
T _{OCKQ}	CLK to OQ/TQ out.	0.49	0.56	0.56	ns
T _{RQ_OLOGIC}	SR pin to OQ/TQ out.	0.80	0.95	0.95	ns
T _{GSRQ_OLOGIC}	Global set/reset to Q outputs.	7.60	10.51	10.51	ns
Set/Reset					
T _{RPW_OLOGIC}	Minimum pulse width, SR inputs.	0.74	0.74	0.74	ns, Min

Output Serializer/Deserializer Switching Characteristics

Table 24: OSERDES Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Setup/Hold					
T _{OSDCK_D} / T _{OSCKD_D}	D input setup/hold with respect to CLKDIV.	0.45/0.03	0.63/0.03	0.63/0.03	ns
T _{OSDCK_T} / T _{OSCKD_T}	T input setup/hold with respect to CLK.	0.73/−0.13	0.88/−0.13	0.88/−0.13	ns
T _{OSDCK_T2} / T _{OSCKD_T2}	T input setup/hold with respect to CLKDIV.	0.34/−0.13	0.39/−0.13	0.39/−0.13	ns
T _{OSCKCK_OCE} / T _{OSCKC_OCE}	OCE input setup/hold with respect to CLK.	0.34/0.58	0.51/0.58	0.51/0.58	ns
T _{OSCKCK_S}	SR (reset) input setup with respect to CLKDIV.	0.52	0.85	0.85	ns
T _{OSCKCK_TCE} / T _{OSCKC_TCE}	TCE input setup/hold with respect to CLK.	0.34/0.01	0.51/0.01	0.51/0.01	ns
Sequential Delays					
T _{OSCKO_OQ}	Clock to out from CLK to OQ.	0.42	0.48	0.48	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ.	0.49	0.56	0.56	ns
Combinatorial					
T _{OSDO_TTQ}	T input to TQ out.	0.92	1.11	1.11	ns

Table 26: IO_FIFO Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
IO_FIFO Clock to Out Delays					
T _{OFFCKO_DO}	RDCLK to Q outputs.	0.60	0.68	0.68	ns
T _{CKO_FLAGS}	Clock to IO_FIFO flags.	0.61	0.77	0.77	ns
Setup/Hold					
T _{CCK_D} /T _{CKC_D}	D inputs to WRCLK.	0.51/0.02	0.58/0.02	0.58/0.02	ns
T _{IFFCK_WREN} / T _{IFFKC_WREN}	WREN to WRCLK.	0.47/-0.01	0.53/-0.01	0.53/-0.01	ns
T _{OFFCK_RDEN} / T _{OFFKC_RDEN}	RDEN to RDCLK.	0.58/0.02	0.66/0.02	0.66/0.02	ns
Minimum Pulse Width					
T _{PWH_IO_FIFO}	RESET, RDCLK, WRCLK.	2.15	2.15	2.15	ns
T _{PWL_IO_FIFO}	RESET, RDCLK, WRCLK.	2.15	2.15	2.15	ns
Maximum Frequency					
F _{MAX}	RDCLK and WRCLK.	200.00	200.00	200.00	MHz

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 28: CLB Distributed RAM Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Sequential Delays					
T _{SHCKO}	Clock to A – B outputs.	1.09	1.32	1.32	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs.	1.53	1.86	1.86	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK.	0.60/0.30	0.72/0.35	0.72/0.35	ns, Min
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock.	0.30/0.60	0.37/0.70	0.37/0.70	ns, Min
	Address An inputs through MUXs and/or carry logic to clock.	0.77/0.21	0.94/0.26	0.94/0.26	ns, Min
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock.	0.43/0.12	0.53/0.17	0.53/0.17	ns, Min
T _{CECK_LRAM} /T _{CKCE_LRAM}	CE input to CLK.	0.44/0.11	0.53/0.17	0.53/0.17	ns, Min
Clock CLK					
T _{MPW_LRAM}	Minimum pulse width.	1.13	1.25	1.25	ns, Min
T _{MCP}	Minimum clock period.	2.26	2.50	2.50	ns, Min

Notes:

1. T_{SHCKO} also represents the CLK to XMUX output. Refer to the timing report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 29: CLB Shift Register Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Sequential Delays					
T _{REG}	Clock to A – D outputs.	1.33	1.61	1.61	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output.	1.77	2.15	2.15	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output.	1.23	1.46	1.46	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{WS_SHFREG} /T _{WH_SHFREG}	WE input.	0.41/0.12	0.51/0.17	0.51/0.17	ns, Min
T _{CECK_SHFREG} /T _{CKCE_SHFREG}	CE input to CLK.	0.42/0.11	0.52/0.17	0.52/0.17	ns, Min
T _{DS_SHFREG} /T _{DH_SHFREG}	A – D inputs to CLK.	0.37/0.37	0.44/0.43	0.44/0.43	ns, Min
Clock CLK					
T _{MPW_SHFREG}	Minimum pulse width.	0.86	0.98	0.98	ns, Min

Table 30: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B.	362.19	297.35	297.35	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC.	460.83	388.20	388.20	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration.	365.10	297.53	297.53	MHz

Notes:

1. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
2. These parameters also apply to synchronous FIFO with DO_REG = 0.
3. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
4. These parameters also apply to multi-rate (asynchronous) and synchronous FIFO with DO_REG = 1.
5. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
6. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
7. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
8. These parameters include both A and B inputs as well as the parity inputs of A and B.
9. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
10. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

DSP48E1 Switching Characteristics

Table 31: DSP48E1 Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock					
T _{DSPDCK_A_AREG} / T _{DSPCKD_A_AREG}	A input to A register CLK.	0.30/ 0.13	0.37/ 0.14	0.37/ 0.14	ns
T _{DSPDCK_B_BREG} / T _{DSPCKD_B_BREG}	B input to B register CLK.	0.38/ 0.16	0.45/ 0.18	0.45/ 0.18	ns
T _{DSPDCK_C_CREG} / T _{DSPCKD_C_CREG}	C input to C register CLK.	0.20/ 0.19	0.24/ 0.21	0.24/ 0.21	ns
T _{DSPDCK_D_DREG} / T _{DSPCKD_D_DREG}	D input to D register CLK.	0.32/ 0.27	0.42/ 0.27	0.42/ 0.27	ns
T _{DSPDCK_ACIN_AREG} / T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK.	0.27/ 0.13	0.32/ 0.14	0.32/ 0.14	ns
T _{DSPDCK_BCIN_BREG} / T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK.	0.29/ 0.16	0.36/ 0.18	0.36/ 0.18	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock					
T _{DSPDCK_{A,B}_MREG_MULT} / T _{DSPCKD_{A,B}_MREG_MULT}	{A, B} input to M register CLK using multiplier.	2.76/ -0.01	3.29/ -0.01	3.29/ -0.01	ns
T _{DSPDCK_{A,D}_ADREG} / T _{DSPCKD_{A,D}_ADREG}	{A, D} input to AD register CLK.	1.48/ -0.02	1.76/ -0.02	1.76/ -0.02	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock					
T _{DSPDCK_{A,B}_PREG_MULT} / T _{DSPCKD_{A,B}_PREG_MULT}	{A, B} input to P register CLK using multiplier.	4.60/ -0.28	5.48/ -0.28	5.48/ -0.28	ns
T _{DSPDCK_D_PREG_MULT} / T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier.	4.50/ -0.73	5.35/ -0.73	5.35/ -0.73	ns
T _{DSPDCK_{A,B}_PREG} / T _{DSPCKD_{A,B}_PREG}	A or B input to P register CLK not using multiplier.	1.98/ -0.28	2.35/ -0.28	2.35/ -0.28	ns
T _{DSPDCK_C_PREG} / T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier.	1.76/ -0.26	2.10/ -0.26	2.10/ -0.26	ns
T _{DSPDCK_PCIN_PREG} / T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK.	1.51/ -0.15	1.80/ -0.15	1.80/ -0.15	ns
Setup and Hold Times of the CE Pins					
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} / T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK.	0.42/ 0.08	0.52/ 0.11	0.52/ 0.11	ns
T _{DSPDCK_CEC_CREG} / T _{DSPCKD_CEC_CREG}	CEC input to C register CLK.	0.34/ 0.11	0.42/ 0.13	0.42/ 0.13	ns
T _{DSPDCK_CED_DREG} / T _{DSPCKD_CED_DREG}	CED input to D register CLK.	0.43/ -0.03	0.52/ -0.03	0.52/ -0.03	ns

Table 31: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
T _{DSPDO_PCIN_CARRYCASCOUT}	PCIN input to CARRYCASCOUT output.	1.56	1.85	1.85	ns
Clock to Outs from Output Register Clock to Output Pins					
T _{DSPCKO_P_PREG}	CLK PREG to P output.	0.37	0.44	0.44	ns
T _{DSPCKO_CARRYCASCOUT_PREG}	CLK PREG to CARRYCASCOUT output.	0.59	0.69	0.69	ns
Clock to Outs from Pipeline Register Clock to Output Pins					
T _{DSPCKO_P_MREG}	CLK MREG to P output.	1.93	2.31	2.31	ns
T _{DSPCKO_CARRYCASCOUT_MREG}	CLK MREG to CARRYCASCOUT output.	2.21	2.64	2.64	ns
T _{DSPCKO_P_ADREG_MULT}	CLK ADREG to P output using multiplier.	3.10	3.69	3.69	ns
T _{DSPCKO_CARRYCASCOUT_ADREG_MULT}	CLK ADREG to CARRYCASCOUT output using multiplier.	3.38	4.02	4.02	ns
Clock to Outs from Input Register Clock to Output Pins					
T _{DSPCKO_P_AREG_MULT}	CLK AREG to P output using multiplier.	4.51	5.37	5.37	ns
T _{DSPCKO_P_BREG}	CLK BREG to P output not using multiplier.	1.87	2.22	2.22	ns
T _{DSPCKO_P_CREG}	CLK CREG to P output not using multiplier.	1.93	2.30	2.30	ns
T _{DSPCKO_P_DREG_MULT}	CLK DREG to P output using multiplier.	4.48	5.32	5.32	ns
Clock to Outs from Input Register Clock to Cascading Output Pins					
T _{DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}}	CLK (ACOUT, BCOUT) to {A,B} register output.	0.73	0.87	0.87	ns
T _{DSPCKO_CARRYCASCOUT_{AREG; BREG}_MULT}	CLK (AREG, BREG) to CARRYCASCOUT output using multiplier.	4.79	5.70	5.70	ns
T _{DSPCKO_CARRYCASCOUT_BREG}	CLK BREG to CARRYCASCOUT output not using multiplier.	2.15	2.55	2.55	ns
T _{DSPCKO_CARRYCASCOUT_DREG_MULT}	CLK DREG to CARRYCASCOUT output using multiplier.	4.76	5.65	5.65	ns
T _{DSPCKO_CARRYCASCOUT_CREG}	CLK CREG to CARRYCASCOUT output.	2.21	2.63	2.63	ns
Maximum Frequency					
F _{MAX}	With all registers used.	550.66	464.25	464.25	MHz
F _{MAX_PATDET}	With pattern detector.	465.77	392.93	392.93	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG.	305.62	257.47	257.47	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect.	277.62	233.92	233.92	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG.	346.26	290.44	290.44	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect.	346.26	290.44	290.44	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG).	227.01	190.69	190.69	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect.	211.15	177.43	177.43	MHz

Table 38: PLL Specification

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
PLL_F _{BANDWIDTH}	Low PLL bandwidth at typical.	1.00	1.00	1.00	MHz
	High PLL bandwidth at typical. ⁽¹⁾	4.00	4.00	4.00	MHz
PLL_T _{STATPHAOFFSET}	Static phase offset of the PLL outputs. ⁽²⁾	0.12	0.12	0.12	ns
PLL_T _{OUTJITTER}	PLL output jitter.	Note 3			
PLL_T _{OUTDUTY}	PLL output clock duty-cycle precision. ⁽⁴⁾	0.20	0.20	0.20	ns
PLL_T _{LOCKMAX}	PLL maximum lock time.	100.00	100.00	100.00	μs
PLL_F _{OUTMAX}	PLL maximum output frequency.	800.00	800.00	800.00	MHz
PLL_F _{OUTMIN}	PLL minimum output frequency. ⁽⁵⁾	6.25	6.25	6.25	MHz
PLL_T _{EXTFDVAR}	External clock feedback variation.	< 20% of clock input period or 1 ns Max			
PLL_RST _{MINPULSE}	Minimum reset pulse width.	5.00	5.00	5.00	ns
PLL_F _{PFDMAX}	Maximum frequency at the phase frequency detector.	500.00	450.00	450.00	MHz
PLL_F _{PFDMIN}	Minimum frequency at the phase frequency detector.	19.00	19.00	19.00	MHz
PLL_T _{FBDELAY}	Maximum delay in the feedback path.	3 ns Max or one CLKIN cycle			
Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK					
T _{PLLDCK_DADDR} / T _{PLLCKD_DADDR}	Setup and hold of D address.	1.40/0.15	1.63/0.15	1.63/0.15	ns, Min
T _{PLLDCK_DI} / T _{PLLCKD_DI}	Setup and hold of D input.	1.40/0.15	1.63/0.15	1.63/0.15	ns, Min
T _{PLLDCK_DEN} / T _{PLLCKD_DEN}	Setup and hold of D enable.	1.97/0.00	2.29/0.00	2.29/0.00	ns, Min
T _{PLLDCK_DWE} / T _{PLLCKD_DWE}	Setup and hold of D write enable.	1.40/0.15	1.63/0.15	1.63/0.15	ns, Min
T _{PLLCKO_DRDY}	CLK to out of DRDY.	0.72	0.99	0.99	ns, Max
F _{DCK}	DCLK frequency.	200.00	200.00	200.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the *Clocking Wizard* [Ref 8].
4. Includes global clock buffer.
5. Calculated as FVCO/128 assuming output duty cycle is 50%.

Device Pin-to-Pin Output Parameter Guidelines

Table 39: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Near Clock Region)⁽¹⁾

Symbol	Description	Device	V _{CCINT} Operating Voltage and Speed Grade			Units
			1.0V		0.95V	
			-2	-1	-1L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.						
T _{ICKOF}	Clock-capable clock input and OUTFF at pins/banks closest to the BUFGs <i>without</i> MMCM/PLL (near clock region). ⁽²⁾	XC7S6	5.55	6.50	6.50	ns
		XC7S15	5.55	6.50	6.50	ns
		XC7S25	5.55	6.44	6.44	ns
		XC7S50	5.71	6.62	6.62	ns
		XC7S75	5.73	6.71	6.71	ns
		XC7S100	5.73	6.71	6.71	ns
		XA7S6	5.55	6.50	N/A	ns
		XA7S15	5.55	6.50	N/A	ns
		XA7S25	5.55	6.44	N/A	ns
		XA7S50	5.71	6.62	N/A	ns
		XA7S75	5.73	6.71	N/A	ns
		XA7S100	5.73	6.71	N/A	ns

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Refer to the *Die Level Bank Numbering Overview* section of the *7 Series FPGA Packaging and Pinout Specification* (UG475) [Ref 4].

Table 41: Clock-Capable Clock Input to Output Delay With MMCM⁽¹⁾

Symbol	Description	Device	V _{CCINT} Operating Voltage and Speed Grade			Units
			1.0V		0.95V	
			-2	-1	-1L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, with MMCM.						
T _{ICKOFMMCMCC}	Clock-capable clock input and OUTFF with MMCM. ⁽²⁾	XC7S6	1.03	1.03	1.03	ns
		XC7S15	1.03	1.03	1.03	ns
		XC7S25	1.00	1.00	1.00	ns
		XC7S50	1.00	1.00	1.00	ns
		XC7S75	1.00	1.00	1.00	ns
		XC7S100	1.00	1.00	1.00	ns
		XA7S6	1.03	1.03	N/A	ns
		XA7S15	1.03	1.03	N/A	ns
		XA7S25	1.00	1.00	N/A	ns
		XA7S50	1.00	1.00	N/A	ns
		XA7S75	1.00	1.00	N/A	ns
		XA7S100	1.00	1.00	N/A	ns

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

XADC Specifications

The 7 Series FPGAs Overview (DS180) [Ref 1] and XA Spartan-7 Automotive FPGA Data Sheet: Overview (DS171) [Ref 2] list the devices that contain a 7 series XADC dual 12-Bit 1 MSPS analog-to-digital converter.

Table 50: XADC Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$V_{CCADC} = 1.8V \pm 5\%$, $V_{REFP} = 1.25V$, $V_{REFN} = 0V$, $ADCCLK = 26\text{ MHz}$, $-55^{\circ}\text{C} \leq T_j \leq 125^{\circ}\text{C}$. Typical values at $T_j = +40^{\circ}\text{C}$.						
ADC Accuracy⁽¹⁾						
Resolution			12	–	–	Bits
Integral nonlinearity ⁽²⁾	INL	$-40^{\circ}\text{C} \leq T_j \leq 100^{\circ}\text{C}$	–	–	± 2	LSBs
		$-55^{\circ}\text{C} \leq T_j < -40^{\circ}\text{C}$; $100^{\circ}\text{C} < T_j \leq 125^{\circ}\text{C}$	–	–	± 3	LSBs
Differential nonlinearity	DNL	No missing codes, guaranteed monotonic.	–	–	± 1	LSBs
Offset error	Unipolar	$-40^{\circ}\text{C} \leq T_j \leq 100^{\circ}\text{C}$	–	–	± 8	LSBs
		$-55^{\circ}\text{C} \leq T_j < -40^{\circ}\text{C}$; $100^{\circ}\text{C} < T_j \leq 125^{\circ}\text{C}$	–	–	± 12	LSBs
	Bipolar	$-55^{\circ}\text{C} \leq T_j \leq 125^{\circ}\text{C}$	–	–	± 4	LSBs
Gain error			–	–	± 0.5	%
Offset matching			–	–	4	LSBs
Gain matching			–	–	0.3	%
Sample rate			–	–	1	MS/s
Signal to noise ratio ⁽²⁾	SNR	$F_{SAMPLE} = 500\text{ KS/s}$, $F_{IN} = 20\text{ kHz}$	60	–	–	dB
RMS code noise		External 1.25V reference.	–	–	2	LSBs
		On-chip reference.	–	3	–	LSBs
Total harmonic distortion ⁽²⁾	THD	$F_{SAMPLE} = 500\text{ KS/s}$, $F_{IN} = 20\text{ kHz}$	70	–	–	dB
Analog Inputs⁽³⁾						
ADC input ranges		Unipolar operation.	0	–	1	V
		Bipolar operation.	–0.5	–	+0.5	V
		Unipolar common mode range (FS input).	0	–	+0.5	V
		Bipolar common mode range (FS input).	+0.5	–	+0.6	V
Maximum external channel input ranges		Adjacent analog channels set within these ranges should not corrupt measurements on adjacent channels.	–0.1	–	V_{CCADC}	V
Full-resolution bandwidth	FRBW	Auxiliary channel full resolution bandwidth.	250	–	–	kHz
On-chip Sensors						
Temperature sensor error		$-40^{\circ}\text{C} \leq T_j \leq 100^{\circ}\text{C}$	–	–	± 4	$^{\circ}\text{C}$
		$-55^{\circ}\text{C} \leq T_j < -40^{\circ}\text{C}$; $100^{\circ}\text{C} < T_j \leq 125^{\circ}\text{C}$	–	–	± 6	$^{\circ}\text{C}$
Supply sensor error		$-40^{\circ}\text{C} \leq T_j \leq 100^{\circ}\text{C}$	–	–	± 1	%
		$-55^{\circ}\text{C} \leq T_j < -40^{\circ}\text{C}$; $100^{\circ}\text{C} < T_j \leq 125^{\circ}\text{C}$	–	–	± 2	%

Table 50: XADC Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
Conversion Rate⁽⁴⁾						
Conversion time: continuous	t_{CONV}	Number of ADCCLK cycles.	26	–	32	Cycles
Conversion time: event	t_{CONV}	Number of CLK cycles.	–	–	21	Cycles
DRP clock frequency	DCLK	DRP clock frequency.	8	–	250	MHz
ADC clock frequency	ADCCLK	Derived from DCLK.	1	–	26	MHz
DCLK duty cycle			40	–	60	%
XADC Reference⁽⁵⁾						
External reference	V_{REFP}	Externally supplied reference voltage.	1.20	1.25	1.30	V
On-chip reference		Ground V_{REFP} pin to AGND, $-40^{\circ}\text{C} \leq T_j \leq 100^{\circ}\text{C}$	1.2375	1.25	1.2625	V
		Ground V_{REFP} pin to AGND, $-55^{\circ}\text{C} \leq T_j < -40^{\circ}\text{C}; 100^{\circ}\text{C} < T_j \leq 125^{\circ}\text{C}$	1.225	1.25	1.275	V

Notes:

- Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
- Only specified for bitstream option XADCEnhancedLinearity = ON.
- For a detailed description, see the ADC chapter in the *7 Series FPGAs and Zynq-7000 AP SoC XADC Dual 12-Bit 1 MSPS Analog-to-Digital Converter User Guide* (UG480) [Ref 9].
- For a detailed description, see the *Timing* chapter in the *7 Series FPGAs and Zynq-7000 AP SoC XADC Dual 12-Bit 1 MSPS Analog-to-Digital Converter User Guide* (UG480) [Ref 9].
- Any variation in the reference voltage from the nominal $V_{REFP} = 1.25\text{V}$ and $V_{REFN} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by $\pm 4\%$ is permitted.

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